## **QE Semiconductor : Electronic devices (40 points)**

**Physical Constants** 

Electronic charge, q=1.6×10<sup>-19</sup>C

 $\epsilon_0 = 8.85 \times 10^{-14} F/cm$ 

Relative Dielectric constant of Si  $\epsilon_{r,Si}$  =11.8 Relative Dielectric constant of SiO<sub>2</sub>  $\epsilon_{r,SiO2}$  =3.9

- 1. (MOSFET) Supposed an ideal nMOSFET is operated at room temperature. Using the square-law results,
  - a) (10 pts) when  $V_D>0$  and  $V_G-V_D=V_T/2$ : derive the  $I_D$  equation and sketch the inversion layer and depletion region inside the MOSFET with labeling all parts of the device.
  - **b**) (10 pts) when  $V_D>0$  and  $V_G-V_D=2V_T$ : repeat (a)
- 2. (BJT) Consider a pnp BJT where  $I_{Ep}=1mA,~I_{En}=0.01~mA,~I_{Cp}=0.98~mA,$  and  $I_{Cn}=0.1~\mu A.$  Calculate
  - a)  $(10 \text{ pts}) \gamma \text{ and } I_B$
  - **b**)  $(10 \text{ pts}) \beta$